

Notice of References Cited	Application/Control No. 10/672,863	Applicant(s)/Patent Under Reexamination EDNEY ET AL.	
	Examiner James Kish	Art Unit 3737	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0100864	08-2002	Wake, Robert H.	250/208.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Slepicka et al., Stabilized Non-Linear Regression for Interferogram Analysis, 10 August 1995, Applied Optics, Vol. 34, No. 23, pages 5039-5044
	V	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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